Special Issue

Machine Learning-Based Medical Image Analysis

Message from the Guest Editors

Machine learning and deep learning techniques have contributed to great success in medical image analysis. This Special Issue is being assembled to share various in-depth research results related to machine-learning and deep-learning-based medical image analysis methods, including, but not limited to, organ segmentation, detection of particular regions of interest, disease diagnosis and quantification, prediction of prognosis, and image restoration and synthesis. These applications may utilize various types of medical imaging modalities, such as X-ray, computerized tomography (CT), magnetic resonance imaging (MRI), positron emission tomography (PET), ultrasound, mammography, and pathological images. It is our pleasure to invite you to join this Special Issue, entitled "Machine Learning-Based Medical Image Analysis", whereby you are welcome to contribute a manuscript on your valuable research progress. Thank you very much.

Guest Editors

Prof. Dr. Soo-Hyung Kim

Prof. Ilwoo Park

Dr. Inseop Na

Deadline for manuscript submissions closed (1 August 2023)



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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